

**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

1761

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	1/20/2006	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
426	614, 521		
	524	1/20/2006	AW

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PGPub Text Search	1/20/2006	AW